

**IN THE CLAIMS**

Please amend the claims as follows:

1. (Canceled)
2. (Currently amended) The multichip module according to claim 4 ~~[[1]]~~, wherein said test means controls all the states of said plurality of input/output cells that are commonly connected to the same external terminals.
3. (Currently amended) The multichip module according to claim 4 ~~[[1]]~~, wherein said test means controls all the states of said plurality of input/output cells of the semiconductor chips.
4. (Currently amended) A multichip module comprising a plurality of semiconductor chips mounted on said multichip module, wherein each said plurality of semiconductor chips includes at least a plurality of input/output cells connected to a plurality of respective external terminals of the multichip module, and testing means for optionally setting states of said plurality of input/output cells,

~~The multichip module according to any of claims 1 to 3,~~

wherein said test means includes:

- a first set ~~sets~~ of plural flip-flops of which configuration is based on that of a shift register;
- a second set ~~sets~~ of plural flip-flops of which inputs are connected to corresponding outputs of the first set ~~sets~~ of plural flip-flops; and
- a selector for selecting a normal signal in a non-test mode, while selecting an output from the second set ~~sets~~ of flip-flops in a test mode, so as to give an input/output control signal to said plurality of input/output cells.

- 5-6. (Canceled)